

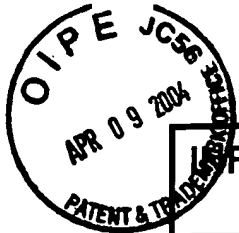


<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT Sheet 1 of 2</b>		Docket No. B0004/7116
Applicant:	Gerhard Weiß	
Serial No:	10/688,207	
Filed:	October 17, 2003	
For:	COMPACT VERY HIGH RESOLUTION TIME-OF-FLIGHT MASS SPECTROMETER	
Examiner:	Not Yet Assigned	
Art Unit:	Not Yet Assigned	

U.S. PATENT DOCUMENTS					
Exam Inits	Cite No.	Patent Number	Kind Code	Patentee or Applicant Name	Issue Date
		3,863,068	B1	Poschenrieder	1/1975
		6,300,625	B1	Ishihara	10/2001

FOREIGN PATENT DOCUMENTS							
Exam Inits	Cite No.	Cy	Number	Kind Code	Patentee or Applicant Name	Publication Date	T
		DE	2045 338	A1	Shell Internationale Research Maatschappij N.V.	9/14/1970	<input type="checkbox"/>
		JP	11135061	A	Jeol Ltd.	5/21/1999	<input type="checkbox"/>
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Examiner Signature		Date Considered	
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**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT Sheet 2 of 2**

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**OTHER PRIOR ART – NON PATENT LITERATURE AND DOCUMENTS**

Exam Inits	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the articles (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T
		WILEY, W.C., et al., "Time-of-Flight Mass Spectrometer with Improved Resolution", The Review of Scientific Instruments, Vol. 26, No. 12, Bendix Aviation Corporation Research Laboratories, December 1955, pp. 1150-1157.	<input type="checkbox"/>
		BAKKER, J.M., "The Time-Focusing Principle: A Double-Focusing Design For Time-Of-Flight Mass Spectrometers", International Journal of Mass Spectrometry and Ion Physics, Vol. 6, Elsevier Publishing Company, Amsterdam, 1971, pp. 291-295.	<input type="checkbox"/>
		SYSOEV, Alexander A., et al., "Direct sampling time-of-flight mass spectrometers for technological analysis", Fresenius J. Anal Chem, Vol. 361, Springer-Verlag, 1998, pp. 261-266.	<input type="checkbox"/>
		SYSOEV, A.A., "Time-of-flight analysers with sector fields: advances and prospects", Eur. J. Mass Spectrom, Vol. 6, IM Publications, 2000, pp. 501-513.	<input type="checkbox"/>
		SAKURAI, T., et al., "A New Time-Of-Flight Mass Spectrometer", International Journal of Mass Spectrometry and Ion Processes, Vol. 66, No. 3, Elsevier Science Publishers B.V., 1985, pp. 283-290.	<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>

Examiner  
Signature

Date  
Considered